



## CLUSTER DETECTOR TEST REPORT

**CLUSTER DETECTOR No. 17**  
**Test carried on 08.01.12**

Ch.	HEX	U <sub>op</sub> [V]	U <sub>op</sub> – 500 V		U <sub>op</sub>			
			FWHM [keV]	$\frac{FWTM}{FWHM}$	1332 keV			122 keV
					FWHM [keV]	$\frac{FWTM}{FWHM}$	Pos. [Ch.]	FWHM [keV]
A	68	3500	1.96	n.c.	1.95	n.c.	6320	
B	124	3500	2.01	n.c.	2.01	n.c.	6790	
C	170	3000	2.06	n.c.	1.98	n.c.	5992	
D	57	3000	1.96	n.c.	1.87	n.c.	5957	
E	154	3500	2.09	n.c.	1.83	n.c.	6658	
F	151	3500	2.09	n.c.	1.97	n.c.	3536	
G	58	3000	1.98	n.c.	1.87	n.c.	9778	

**Operational Temperature: -160.0 °C**

**Date: 08.01.2012**

**Tested by:**  
**/I.Kojouharov/**

### **Assembly and test remarks:**

Regular test after assembly at RIKEN.

All line positions less than ch. 4096 or more than ch. 8192 are recalculated based on the amplifier gain.

### **Test Equipment:**

HV – ORTEC 660

Main Amplifier – ORTEC 671,  $\tau = 6 \mu\text{s}$ , gain 100 x 0.72

ADC – 4801A (RIKEN), MCA - PC98B

Source -  $^{60}\text{Co}$